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ISSUE CLASSIFICATION	
Class	Subclass

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E. 1 SCANNED <i>Bw</i> O.A. <i>CTH</i>	PATENT DATE
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APPLICATION NO. 09/714183	CONT/PRIOR F	CLASS 356	SUBCLASS 124	ART UNIT 2877	EXAMINER <i>Purnoose</i>
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APPLICANTS

Hitoshi Takeuchi

TITLE

Aberration measuring apparatus, aberration measuring method,
projection exposure apparatus having the same measuring apparatus,
device manufacturing method using the same measuring method, and
exposure method

PTO-2040
12/99

PTO-2040
12/98**ISSUING CLASSIFICATION**[illegible]

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
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<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent. No. _____ _____ _____	_____ (Primary Examiner) _____ (Date)		ISSUE FEE	
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